

Selective Control of Test-Access Ports in Integrated Circuits

Abstract of the Disclosure

To facilitate testing, some integrated circuits include built-in test
5 circuits, called test-access ports (TAPs). The present inventor recognized that
TAPs are sometimes used with automatic testers that have limitations, such as
insufficient memory capacity, that make it difficult or costly to test some
integrated circuits, such as microprocessors. Accordingly, this disclosure
teaches, among other things, inputting test signals to a TAP of an integrated
10 circuit using a first device, such as an automatic tester, and outputting state
data related to the input test signals from the TAP using a second device.

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